

FNK N-Channel Enhancement Mode Power MOSFET

General Description

The FNK06N02C combines advanced trench MOSFET technology with a low resistance package to provide extremely low $R_{\text{DS(ON)}}$. This device is ideal for load switch and battery protection applications.

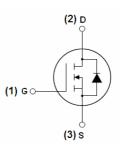
Product Summary

 $\begin{array}{ll} V_{DS} & 20V \\ I_{D} \; (at \; V_{GS}\!\!=\!\!4.5V) & 75A \\ R_{DS(ON)} \; (at \; V_{GS}\!\!=\!\!4.5V) & < 5.4 m\Omega \\ R_{DS(ON)} \; (at \; V_{GS}\!\!=\!\!2.5V) & < 7.2 m\Omega \end{array}$

- High Power and current handing capability
- Lead free product is acquired

Application

- Battery Switch
- Load switch
- Power management



Schematic diagram



TO-251 top view

Absolute Maximum	Ratings T _A =25℃ unles	s otherwise noted		
Parameter		Symbol	Maximum	Units
Drain-Source Voltage		V _{DS}	20	V
Gate-Source Voltage		V_{GS}	±12	V
Continuous Drain	T _C =25℃		75	
Current ^G	T _C =100℃	'D	55	A
Pulsed Drain Current ^C		I _{DM}	300	\exists
Avalanche Current ^C		I _{AS}	56	A
Avalanche energy L=0.5mH ^C		E _{AS}	97	mJ
	T _C =25℃	P _D	100	W
Power Dissipation ^B	T _C =100℃	T'D	50	
Junction and Storage Temperature Range		T _J , T _{STG}	-55 to 175	C

Thermal Characteristics	Characteristics				
Parameter		Symbol	Тур	Max	Units
Maximum Junction-to-Ambient A	t ≤ 10s	D	16	20	℃/W
Maximum Junction-to-Ambient AD	Steady-State	$R_{\theta JA}$	41	50	€/M
Maximum Junction-to-Case	Steady-State	$R_{\theta JC}$	2.2	2.5	℃/W

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Electrical Characteristics (T_J=25℃ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Тур	Max	Units	
STATIC PARAMETERS							
BV _{DSS}	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	20			V	
	Zero Gate Voltage Drain Current	V _{DS} =20V, V _{GS} =0V			1		
I _{DSS}		T _J =55℃			5	μΑ	
I _{GSS}	Gate-Body leakage current	V_{DS} =0V, V_{GS} = ±12V			100	nA	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS} I_{D}=250\mu A$	0.5	0.7	1.6	V	
I _{D(ON)}	On state drain current	V_{GS} =10V, V_{DS} =5V	160			Α	
R _{DS(ON)} St	Static Drain-Source On-Resistance	V_{GS} =4.5V, I_{D} =20A		4.3	5.4	mΩ	
		V _{GS} =2.5V, I _D =20A		5.6	7.2	mΩ	
g _{FS}	Forward Transconductance	V_{DS} =5V, I_{D} =20A		105		S	
V_{SD}	Diode Forward Voltage	I _S =1A,V _{GS} =0V		0.7	1	V	
I _S	Maximum Body-Diode Continuous Current ^G				45	Α	
DYNAMIC	PARAMETERS						
С	Input Capacitance		2680			pF	
С	Output Capacitance	V_{GS} =0V, V_{DS} =10V, f=1MHz	345		pF		
С	Reverse Transfer Capacitance]	320			pF	
R	Gate resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz	1.4			Ω	
SWITCHI	NG PARAMETERS						
Q _g (4.5V)	Total Gate Charge		28	36	43	nC	
Q_{gs}	Gate Source Charge	V_{GS} =10V, V_{DS} =10V, I_{D} =20A		9		nC	
Q_{gd}	Gate Drain Charge]		12		nC	
t _{D(on)}	Turn-On DelayTime			7		ns	
t _r	Turn-On Rise Time	V_{GS} =10V, V_{DS} =10V, R_L =0.5 Ω ,		8		ns	
t _{D(off)}	Turn-Off DelayTime	R_{GEN} =3 Ω		70		ns	
t _f	Turn-Off Fall Time	<u>]</u>		18		ns	
t _{rr}	Body Diode Reverse Recovery Time	I_F =20A, dI/dt=500A/ μ s	13	17	20	ns	
Q_{rr}	Body Diode Reverse Recovery Charge	I_F =20A, dI/dt=500A/ μ s	29	36	43	nC	

A. The value of $R_{\theta JA}$ is measured with the device mounted on $1in^2$ FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^{\circ}$ C. The Power dissipation P_{DSM} is based on R _{θJA} and the maximum allowed junction temperature of 150° C. The value in any given application depends on the user's specific board design, and the maximum temperature of 175° C may be used if the PCB allows it.

B. The power dissipation P_D is based on $T_{J(MAX)}=175^\circ$ C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature T_{J(MAX)}=175° C. Ratings are based on low frequency and duty cycles to keep initial T_J=25° C.

D. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to case $R_{\theta JC}$ and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300µs pulses, duty cycle 0.5% max.

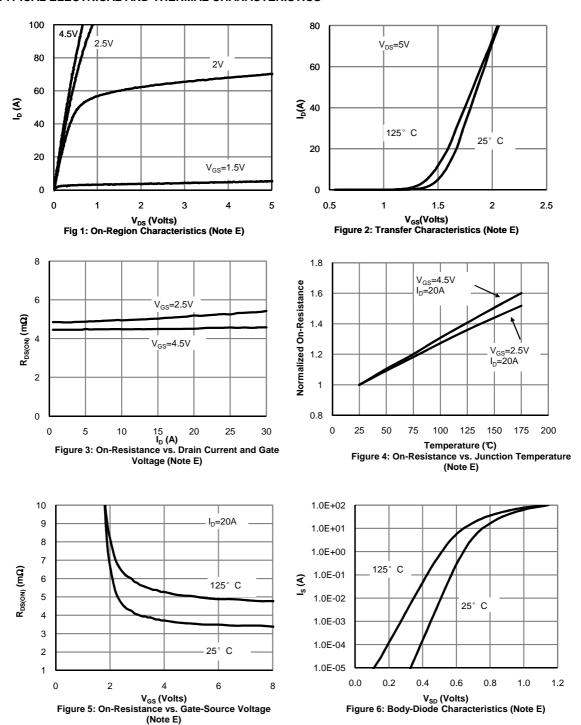
F. These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}$ =175° C. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25° C.



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS





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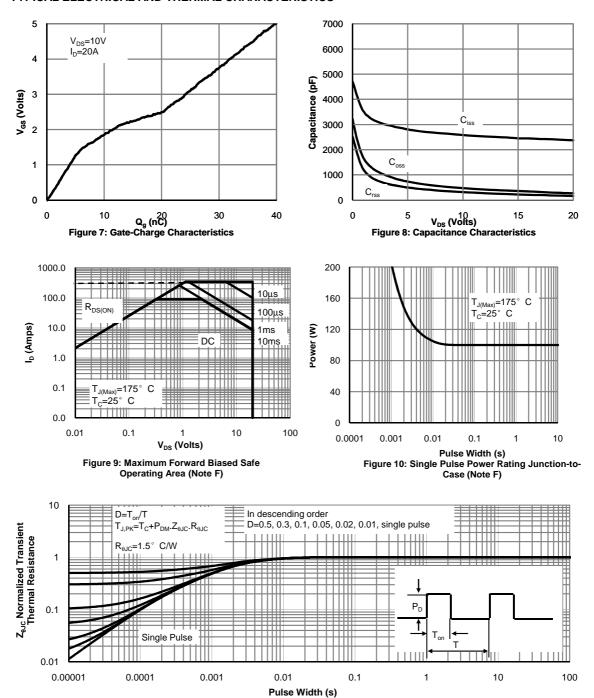
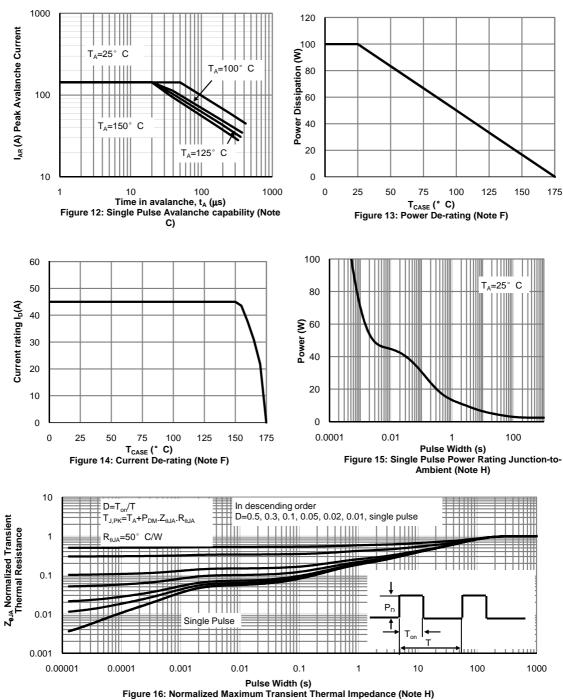


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

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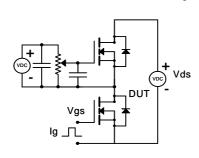
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

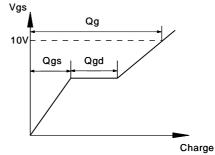


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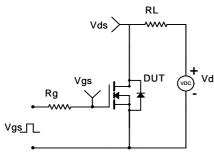


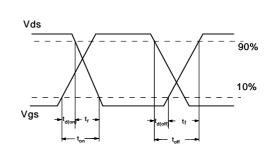
Gate Charge Test Circuit & Waveform



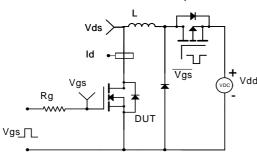


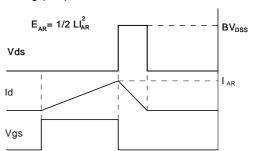
Resistive Switching Test Circuit & Waveforms



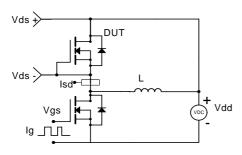


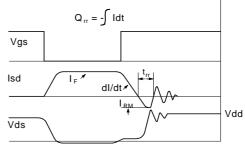
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





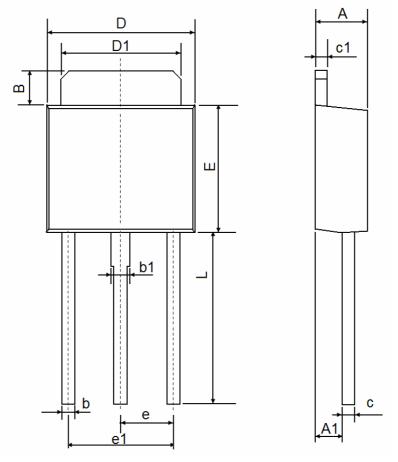
Diode Recovery Test Circuit & Waveforms







TO-251 Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
А	2.200	2.400	0.087	0.094
A1	1.050	1.350	0.042	0.054
В	1.350	1.650	0.053	0.065
b	0.500	0.700	0.020	0.028
b1	0.700	0.900	0.028	0.035
С	0.430	0.580	0.017	0.023
c1	0.430	0.580	0.017	0.023
D	6.350	6.650	0.250	0.262
D1	5.200	5.400	0.205	0.213
Е	5.400	5.700	0.213	0.224
е	2.300 TYP.		0.091 T	YP.
e1	4.500	4.700	0.177	0.185
L	7.500	7.900	0.295	0.311



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